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107th ARFTG Microwave Measurement Conference

Measuring the Future: High-Frequency Metrology for Intelligent, Connected, and Quantum Worlds

Boston, MA | June 12, 2026

Co-located with IMS-2026

» Call for Papers | Abstract Due: February 27th, 2026

Suggested topics include, but are not limited to:

- High-frequency metrology and traceability of electrical quantities
- Calibration and measurement techniques for future communication systems and sensing applications
- New measurement instrumentation
- Cryogenic measurements for quantum and radio astronomy applications
- Microwave measurement techniques applied to AI technologies
- Non-linear measurements
- Metrology for EO/OE interfaces and photonic integrated circuits

Outstanding exhibition and corporate sponsorship opportunities:

Please contact our Exhibits Chair Joel Dunsmore: exhibits@arftg.org or our Sponsors Chair Chong Li: sponsorship@arftg.org directly for further information.

www.arftg.org

107th ARFTG Microwave Measurement Conference

CALL FOR PAPERS

The theme of the 107th ARFTG Conference (co-located with IMS-2026) is **"Measuring the Future: High-Frequency Metrology for Intelligent, Connected, and Quantum Worlds"**. We invite submissions of original papers showcasing innovative measurement techniques that support the development of future communication, quantum and sensing systems. Contributions covering all aspects of RF, microwave, millimeter-wave, and sub-THz measurements are welcome. Suggested topics include, but are not limited to:

- High-frequency metrology and traceability of electrical quantities
- Calibration and measurement techniques for future communication systems and sensing applications
- New measurement instrumentation
- Cryogenic measurements for quantum and radio astronomy applications
- Microwave measurement techniques applied to AI technologies
- Non-linear measurements
- Metrology for EO/OE interfaces and photonic integrated circuits

Topics always of interest include:

- On-wafer calibration and measurements
- Large signal measurements incl. linearization of devices, circuits, and systems
- Characterization of material properties
- RF/digital mixed-signal measurement and calibration
- Millimeter-wave antennas, OTA testing, and RIS testing
- Other recent developments in metrology incl. measurement uncertainty

DEADLINES

February 27, 2026	**Abstract Submission Due**
March 20, 2026	Paper acceptance and classification notification
April 10, 2026	Publication-ready paper is due in PDF format

INSTRUCTIONS FOR AUTHORS

Authors are strongly encouraged to use the template on that webpage to prepare both initial paper and final paper submissions.

We request that authors submit an initial paper (4 pages or less) with supporting figures of both experimental setups and measurement results to enable evaluation with respect to the interests of the participants and the novelty of the work.

Contributed papers will be presented as 20-minute talks or in an interactive poster session. Final papers will be published as part of the ARFTG proceedings in IEEE Xplore, provided it has been presented at the conference.

More details can be found on the ARFTG website:
https://arftg.org/author-instruction

Version: 1.1: May 19, 2025

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